



Colloquium

Department of Engineering and
System Science,
Institute of Nuclear Engineering
and Science,
National Tsing Hua University

Surface and thin film analytical
technique by X-ray diffraction

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In this talk, the following content will be presented:

X-ray diffraction (XRD) technology provide information of crystal structure and strain state of material. X-ray reflectivity (XRR) is one another X-ray technique to characterize surfaces and layer structure of thin films and multilayers.

By high flux, high resolution and wide energy range, TLS b1 17b1 provides high quality of X-ray beam source that could enhance the quality of data.

15:30-17:00, Wednesday, Nov. 30th, 2022

NE69 ESS Building, NTHU

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Biography:



- Assistant scientist at National Synchrotron Radiation Research Center (NSRRC), Oct.2012 – current.
- Ph.D. of Engineering, Dept. of Engineering and System Science, NTHU, Sep.2006 - Jun.2012
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